



JPW

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of:

Hae-seok PARK et al.

Art Unit: 2862

Serial No. 10/763,394

Examiner: David M. Schindler

Filed: January 26, 2004

Confirmation No. 4583

For: FLUXGATE SENSOR INTEGRATED IN A  
SEMICONDUCTOR SUBSTRATE AND  
METHOD FOR MANUFACTURING THE  
SAME

Attorney Docket No. 277/044

**AMENDMENT UNDER 37 C.F.R. § 1.111**

Mail Stop Amendment  
Commissioner for Patents  
United States Patent and Trademark Office  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INTRODUCTORY COMMENTS**

In response to the Office action dated December 16, 2005 and the March 15, 2006 personal interview, the following amendments and remarks are respectfully submitted in connection with the above-identified application:

**Amendments to the Claims** are reflected in a listing of claims, which begins on page 2 of this paper.

**Remarks** begin on page 11 of this paper.